

**IN THE CLAIMS:**

1. (Currently Amended) A calibration pattern unit photographed by an imaging system to acquire an image for obtaining ~~which obtains~~ correction information of ~~an~~ the imaging system by ~~imaging at the imaging system and is formed by combining a plurality of three-dimensionally arranged planes, the unit comprising:~~

a calibration pattern comprising a predetermined pattern for obtaining correction information of the imaging system; and

~~supporting members each of which has a predetermined surface corresponding to one of the planes; and~~

~~a calibration pattern in which a predetermined pattern is formed on the predetermined surface of the supporting member, wherein~~

the supporting member members having a surface formed by three-dimensionally arranged planes, a predetermined one of the surfaces of the supporting members including the calibration pattern formed thereon, and the supporting members being configured to ~~can~~ selectively set the calibration pattern unit ~~to~~ in a first form for photographing when the correction information is obtained, and a second form for other purposes.

2. (Original) The unit according to claim 1, wherein a volume occupied by the first form is larger than that occupied by the second form.

3. (Original) The unit according to claim 2, wherein in the first form, normals of the predetermined surfaces constituting the supporting members are arranged orthogonally to one another.

4. (Original) The unit according to claim 1, wherein in the second form, the predetermined surfaces constituting the supporting members are arranged roughly in parallel with one another.

5. (Original) The unit according to claim 1, wherein in the second form, a surface of the supporting member in which the calibration pattern is not formed is exposed to the outside.

6. (Original) The unit according to claim 5, further comprising:

protection sections configured to prevent direct contact between the supporting member and the calibration pattern and between the calibration patterns themselves in the second form.

7. (Original) The unit according to claim 5, further comprising:

spacer sections configured to prevent contact between the supporting member and the calibration pattern and between the calibration patterns themselves in the second form.

8. (Original) The unit according to claim 1, further comprising:

connection sections which can separate and rejoin the plurality of supporting members from/to one another.

9. (Original) The unit according to claim 1, further comprising:

connection sections configured to change relative positions and postures of the predetermined surfaces of the supporting members while the predetermined surfaces are connected.

10. (Original) The unit according to claim 9, further comprising:

fixing tools configured to fix relative positions of the predetermined surfaces of the supporting members.

11. (Original) The unit according to claim 1, further comprising:

folding sections configured to change relative positions and postures of the predetermined surfaces of the supporting members without releasing connection between the predetermined surfaces themselves.

12. (Original) The unit according to claim 11, further comprising:

fixing tools configured to fix relative positions of the predetermined surfaces of the supporting members.

13. (Currently Amended) A calibration pattern unit photographed by an imaging system to acquire an image for obtaining ~~which obtains~~ correction information of an imaging system by ~~imaging at the imaging system,~~ the unit comprising:

a calibration pattern comprising a predetermined pattern for obtaining correction information of the imaging system; and

supporting members having a surface by at least one of a ~~each of which has a~~ predetermined surface corresponding to one of one plane of three-dimensionally arranged plane[[s]] and ~~one~~ curved surface, a predetermined one of the surfaces of the supporting members including the calibration pattern formed thereon, and the supporting members being configured to selectively set the calibration pattern unit in a first form for photographing when

the correction information is obtained, and in a second form for other purposes of three-  
dimensionally arranged curved surfaces; and

a calibration pattern in which the predetermined pattern is formed on a predetermined  
surface of the supporting member, wherein

the supporting member has first use for photographing when the correction information is  
obtained, and second use for other purposes.

14. (Original) The unit according to claim 13, wherein the second use is for packing the imaging system.

15. (Original) The unit according to claim 13, wherein the second use is for protecting the imaging system.

16. (Currently Amended) A calibration pattern unit photographed by an imaging system to  
acquire an image for obtaining ~~which obtains~~ correction information of ~~an~~ the imaging system ~~by~~  
~~imaging at the imaging system, the unit~~ comprising:

a calibration pattern comprising a predetermined pattern for obtaining correction  
information of the imaging system; and

supporting members having a surface formed by each of which has a predetermined  
surface corresponding to one of one curved surface of a three-dimensionally arranged plane and  
curved surface[[s]], a predetermined one of the surfaces of the supporting members including the  
calibration pattern formed thereon, and the supporting members being configured to selectively  
set the calibration pattern unit in a first form for photographing when the correction information

is obtained, and in a second form for other purposes. and one plane of three dimensionally arranged planes; and

a calibration pattern in which a predetermined pattern is formed on the predetermined surface of the supporting member, wherein

the supporting member can selectively set the calibration pattern unit to a first form for photographing when the correction information is obtained, and a second form for other purposes.

17. (Currently Amended) A calibration pattern unit photographed by an imaging system to acquire an image for obtaining ~~which obtains~~ correction information of ~~an~~ the imaging system by ~~imaging at the imaging system, the unit~~ comprising:

a calibration pattern comprising a predetermined pattern for obtaining correction information of the imaging system;

a framework member with a flexibility; and

a supporting member, made of a flexible material, and configured to use a tensile force generated by fixing the framework member in a predetermined position so as to form surfaces by at least to be formed in a shape combining one of a three-dimensionally arranged plane and curved surface[[s]], and three-dimensionally arranged planes a predetermined one of the surfaces of the supporting member including the calibration pattern formed thereon.; and

a calibration pattern in which a predetermined pattern is formed on a predetermined surface of the supporting member.

18. (Original) The unit according to claim 17, wherein the framework member and the supporting member can be separated from each other.

19. (New) The calibration pattern unit according to claim 1, wherein the second form is a form for one of carrying and storing the calibration pattern unit.

20. (New) The calibration pattern unit according to claim 13, wherein the second form is a form for one of carrying and storing the calibration pattern unit.

21. (New) The calibration pattern unit according to claim 16, wherein the second form is a form for one of carrying and storing the calibration pattern unit.

22. (New) A calibration pattern unit photographed by an imaging system to acquire an image for obtaining correction information of the imaging system, the unit comprising:

a calibration pattern comprising a predetermined pattern for obtaining correction information of the imaging system; and

supporting means having a surface formed by three-dimensionally arranged planes, the surface of the supporting means including the calibration pattern formed thereon, and the supporting means selectively setting the calibration pattern unit in a first form for photographing when the correction information is obtained, and in a second form for other purposes.

23. (New) A calibration pattern unit photographed by an imaging system to acquire an image for obtaining correction information of the imaging system, the unit comprising:

a calibration pattern comprising a predetermined pattern for obtaining correction information of the imaging system; and

supporting means having a surface formed by at least one of a three-dimensionally arranged plane and curved surface, the surface of the supporting means including the calibration pattern formed thereon, and the supporting means selectively setting the calibration pattern unit in a first form for photographing when the correction information is obtained, and in a second form for other purposes.

24. (New) A calibration pattern unit photographed by an imaging system to acquire an image for obtaining correction information of the imaging system, the unit comprising:

a calibration pattern comprising a predetermined pattern for obtaining correction information of the imaging system; and

supporting means having a surface formed by a three-dimensionally arranged plane and curved surface, the surface of the supporting means including the calibration pattern formed thereon, and the supporting means selectively setting the calibration pattern unit in a first form for photographing when the correction information is obtained, and in a second form for other purposes.

25. (New) A calibration pattern unit photographed by an imaging system to acquire an image for obtaining correction information of the imaging system, the unit comprising:

a calibration pattern comprising a predetermined pattern for obtaining correction information of the imaging system;

a framework member with a flexibility; and

supporting means for using a tensile force generated by fixing the framework in a predetermined position so as to form a surface by at least one of a three-dimensionally arranged

plane and curved surface, and the surface of the supporting means including the calibration pattern formed thereon.